

9.00-9.40	Invited Paper: Prof F. Fantini , UNI Modena "The Reliability of Electronic Systems in the Space – A Tutorial"	Invited Paper: P. Roustan, ORS "RGA interpretation for optoelectronics module"	Invited Paper: Prof M. Fukuda, UNI Toyohashi,"Degradation and Radiation Damage in Laser Diode - Relation between Space and Telecom Reliability"
9.40-10.20	Invited paper: E. Armandillo,ESA " ESA Strategy for Optoelectronics in Space"	Invited paper: G. Perez, CNES, "Failure analysis tools for optoelectronics"	Invited paper: Y. Tange, JAXA, "Outline of development of the Compact Infrared Camera (CIRC)"
10.20-11.00	Invited paper: M. Comparini,TAS Italy, "TAS strategy for optoelectronics in future satellites"	Invited paper: D. Veyrie, CNES " Hermeticity issues on optoelectronic devices"	ORAL SESSION: O1, O2
11.00-11.20	coffee break	coffee break	coffee break
11.20-12.00	Invited Paper: A. Bensoussan, TAS, "Quality Assurance Guideline for Optoelectronic devices for space application: major progress one year after the ISROS 2009 initiative"	Invited paper I.Gontijo, NASA JPL, "Optoelectronic fiber optic packaging lessons learned for space usage"	ORAL SESSION: O3, O4
12.00-14.00	Lunch	Lunch	Lunch
14.00-14.40	Round table: Optoelectronics in Hi-Rel applications: Constraints, Issues, Rules and Test methods	Invited paper: R.Stevens, LOCKHEED MARTIN, "Lessons learned on fiber optic packaging"	Invited Paper: C. Aupetit UNI Limoges "End of life optoelectronic system performance estimation"
14.40-15.20	Round table: Optoelectronics in Hi-Rel applications: Constraints, Issues, Rules and Test methods	Invited paper: S. Ching, ISOLINK, "Reliability issues on opto parts manufactured by Isolink for space applications"	Invited Paper: X. Breniere SOFRADIR "Qualification strategy for infrared detectors"
15.20-16.00	Round table: Optoelectronics in Hi-Rel applications: Constraints, Issues, Rules and Test methods	Invited paper: A. Kohl, QUANTEL LASER DIODES "Packaging issues on laser stacks"	Invited paper: Prof. J. W. Tomm, MBI-Berlin "New techniques for COD characterization on laser diodes"
16.00-16.20	coffee break	coffee break	coffee break
16.20-17.20	Round table: Optoelectronics in Hi-Rel applications: Constraints, Issues, Rules and Test methods	Bus departure to the Nuragic site of Barumini - Conference Dinner	ORAL SESSION O5-O8
17.20-18.00	Industrial exhibit presentation POSTER presentation Welcome cocktail		'A si biri'- Arrivederci cocktail

- O1 Degradation mechanisms of white LEDs for lighting applications
M.MENEGHINI , G. Mura, M. dal Lago, L. Rodighiero, M. Vanzi, G. Meneghesso, E. Zanoni
- O2 Investigation of the Radiation Response of Optical Fibers for the ExoMars Raman Instrument
M.GOEPPEL, M. Glier, H. Thiele
- O3 Fractal Kinetic of Defects Generation in Laser Diodes: Application to Reliability Assessment
O.GILARD, L.Béchou, Gianandrea Quadri, Mathieu Boutillier
- O4 Defect characterization in irradiated silicon photodiodes
C.CADDEO, G. Quadri, O. Gilard, T. Nuns, P. Arnolda, G. Sun, J. Bourgoïn, S. Makham, M. Vanzi
- O5 Long term in-vacuum aging of 980 nm laser diode pump modules for space applications
G.PEDROZA, L. S. How, L. Bechou, O. Gilard, J.L Goudard and C. Nissim
- O6 Tooling the Selection of an Optical Fiber from its Radiation Sensitivity
M.CAUSSANEL, O. Fruchier, H. Duval, J. Leylavergne, F. Reynaud, O. Gilard, G.Quadri
- O7 Faulty Failure Analyses
G.Mura, M.VANZI
- O8 Prediction of Phototransistor Spectral Responsivity Degradation in a Space Environment using DOE methodology
P.SPEZZIGU, L. Bechou, G. Quadri, O. Gilard, C. Caddeo, Y. Ousten, Massimo Vanzi
- P1 Optimized “Design of Experiments” Methodology for the Prediction of Phototransistor Degradation in a Space
G.QUADRI, P. Spezzigu, C. Caddeo, O. Gilard, L. Bechou, M. Vanzi
- P2 Thermal cycling effects on REMS-GTS thermopiles aboard MSL
C. ARMIENS, E. Sebastián, J. Gómez-Elvira
- P3 The REMS GTS In-Flight Calibration System
E.SEBASTIAN, C. Armiens, J. Gómez-Elvira
- P4 Evaluation results of commercially available InGaAs pin PIN photodiodes modules for space applications
G. PEDROZA, M. Boutillier, L. Bechou, L. S. How, J.R. Burie, F. Laruelle, J. L. Goudard, P. Wolkowicz
- P5 Non Destructive, High Resolution Reliability Analysis Tools for Optoelectronics: Technology Update and Case Studies
M.HERTL, D. Weidmann, I. Richard

- P6 Overview of lifetest means and procedures on optoelectronic devices
L. S. HOW, S. Lhuillier, G. Pedroza, A. Delbergue, F. Rosala
- P7 Microelectronic packaging assembly and qualification process flows of a customized phototransistor array for aerospace optical encoders
M.BREGOLI, P. Bouvier, A. Maglione
- P8 Structural Vibration Control of a Cantilever Beam by MRAC method
L.ROSSI, A. Irace, U. Montanaro, M. Di Bernardo, G.Breglio
- P9 A reconfigurable CMOS imager for real-time spatiotemporal image processing with on-chip ADC
M. BARBARO, Gian Nicola Angotzi